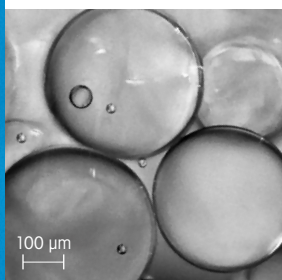


## View and Measure Particles In Situ and in Real Time



### New Experimental Insights

Capture high-resolution images of particles, crystals and droplets, as they exist in situ, to obtain deep process understanding for complex chemical systems. Study crystallization, precipitation, suspensions, and emulsions at previously unobtainable levels of detail and reveal new insights that will power process-development decision-making.



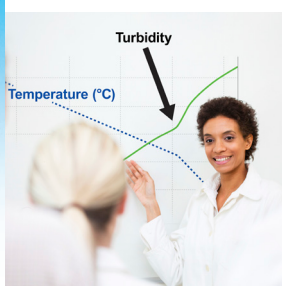
### Powerful Analytics

Transform EasyViewer into a powerful particle size analyzer using image analysis methods in iC Vision. Monitor process changes using simple analytics, or quantify particle size and shape with customized algorithms. Verify results by comparing data with collected images and use this combined information to design the right particles, faster.



### Flexibility for Scale-up

EasyViewer 400 works in the lab or plant thanks to a small probe only instrument and flexible mounting system that inserts in to reactors, pilot vessels and pipelines. Characterization conducted at smaller scales can be compared directly to results obtained during scale-up and transfer de-risking late stage process development.



### Confident Deployment

Leverage auto-focus, auto-lighting, and auto-save-best-image software features to ensure that every project team member can collect the highest quality images from beginning to end of every experiment so that you never miss anything.



### EasyViewer 400

EasyViewer™ 400 is a probe-based imaging tool that captures high-resolution images of crystals, particles, and droplets, as they exist in process. Combined with iC Vision™, an easy-to-use image analysis software, EasyViewer becomes a powerful particle size analyzer that can monitor process changes and quantify particle size and shape in real time. EasyViewer can characterize particle processes across scales, supporting process scale-up, transfer and production. Exceptional information combined with broad usability makes EasyViewer a compelling tool that scientists will enjoy using to accelerate decision-making and speed process-development and scale-up.

# View and Measure Particles

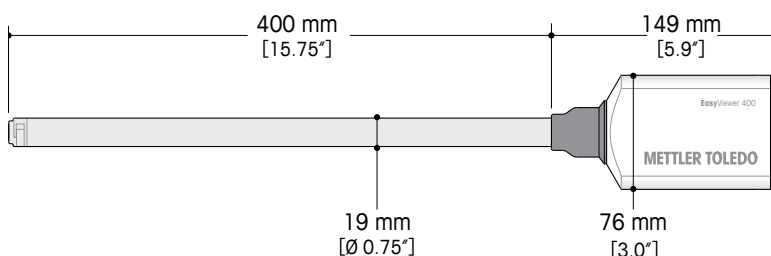
In Situ and in Real Time

## Technical Data

<b>Probe Wetted Material</b>	C22 Alloy, PTFE, Sapphire
<b>Probe Window Material</b>	Sapphire
<b>Probe Diameter</b>	19 mm [0.75 in]
<b>Probe Wetted Length</b>	400 mm [15.75 in]
<b>USB Cable Length</b>	3 m [9.8 ft] (standard); 13 m [42.65 ft] (with USB extender)
<b>Field of View</b>	1100 $\mu\text{m}$ x 800 $\mu\text{m}$ ( $\pm$ 50 $\mu\text{m}$ )
<b>Optical Resolution</b>	> 980 nm
<b>Laser Wavelength</b>	450 nm
<b>Lighting Modes</b>	Front, Back
<b>Probe Weight</b>	1.45kg [3.2 lbs]
<b>Probe Wetted Temperature Range</b>	10 °C to 100 °C (standard); -80 °C to 100 °C (purged)
<b>Probe Back End Temperature Range</b>	0 °C to 40 °C (inserted to 300 mm) 0 °C to 25 °C (inserted to 400 mm)
<b>Probe Wetted Pressure Range</b>	Up to 10 barg (standard); Up to 80 barg (custom)
<b>Air Requirements</b> <small>(use to avoid condensation when operating below dew point)</small>	2.0 barg [30 psig]; 0.5 SLPM (0.02 SCFM) (clean, dry instrument-quality air or Nitrogen purge gas)
<b>Power</b>	USB Extender: 100-240V (auto-switching), 50/60 Hz, 1.7 A
<b>Certification</b>	<b>CE/NRTL-C</b> Approved, Class 1 Laser Device, Compliant with 21CFR1040.10 and 1040.11 and IEC 60825-1.

\*EasyViewer 400 is not rated for explosive locations.

## Probe Dimensions



[www.mt.com/EasyViewer](http://www.mt.com/EasyViewer)

For more information

### METTLER TOLEDO Group

Automated Reactors and In-Situ Analysis  
Local contact: [www.mt.com/contacts](http://www.mt.com/contacts)

Subject to technical changes

© 10/2023 METTLER TOLEDO. All rights reserved